

Search Notes

Application/Control No.

10/629,154

Examiner

Phallaka Kik

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	11,18,3,5	9/16/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	11,18,3,5	9/16/2006	PK
-USPGPUB (see attached)		9/16/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) -USPAT, USPGPUB Cls/sub searched: 716/1-18 (see attached)	9/16/2006	PK
-EPO, JPO, IBM TDB, Derwent (see attached)	9/16/2006	PK
IEE/IEEE XPlore (see attached)	9/15/2006	PK